

<b>Notice of References Cited</b>	Application/Control No. 10/074,500	Applicant(s)/Patent Under Reexamination SUN, FENG-WEN	
	Examiner Krista M. Flanagan	Art Unit 2631	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,560,303	05-2003	Fan et al.	375/365
	B	US-6,466,566	10-2002	De Gaudenzi et al.	370/342
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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